

Notice of References Cited	Application/Control No. 10/756,353	Applicant(s)/Patent Under Reexamination NAGAISHI ET AL.	
	Examiner Hai H. Huynh	Art Unit 3747	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,574,961 B2	06-2003	Shiraishi et al.	60/602
	B	US-			
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	D	US-			
	E	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	O	JP-136528	05-1990	Japan	Kato et al	F02D-41/04
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